

PCN 11_0218

| QUALIFICATION RESULTS | | | |
|--|--------------------------|-------------|-------------|
| TEST | CONDITIONS | SAMPLE SIZE | RESULTS |
| Highly Accelerated Stress Test (HAST)* | JEDEC <i>JESD22-A110</i> | 231 | Pass |
| Temperature Cycle (TC)* | JEDEC <i>JESD22-A104</i> | 231 | Pass |
| Autoclave (AC)* | JEDEC <i>JESD22-A102</i> | 231 | Pass |
| High Temperature Storage Life (HTSL) | JEDEC <i>JESD22-A103</i> | 77 | Pass |
| Solder Heat Resistance (SHR)* | <i>ADI-0049</i> | 33 | Pass |
| Electrostatic Discharge <i>Field-Induced Charged Device Model</i> | JEDEC <i>JESD22-C101</i> | 18 | Pass ±1500V |

*Preconditioned per JEDEC/IPC J-STD-020